

Monolithic Active Pixel Sensors

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Workpackage 3: MAPS

- Who?
 - Birmingham, Imperial, RAL ID, RAL PPD
- Why?
 - Alternative to standard silicon diode pad detectors in ECAL
 - Potential to be cheaper and/or better
- What?
 - Attempt to prove or disprove “MAPS-for-ECAL” concept over next 3 years
- Two-pronged approach: **hardware**...
 - Two rounds of sensor fabrication and testing, including cosmics and sources
 - Electron beam test, to check response in showers and single event upsets
- ...and **simulation**
 - Model detailed sensor response to EM showers and validate against hardware
 - Simulate effect on full detector performance in terms of PFLOW

MAPS history

- Developed over the last decade
 - Integrates sensitive silicon **detector** and **readout electronics** into one device
 - “**Camera on a chip**”; all-in-one device for light detection
 - Standard CMOS technology

Anatomy of the Active Pixel Sensor Photodiode

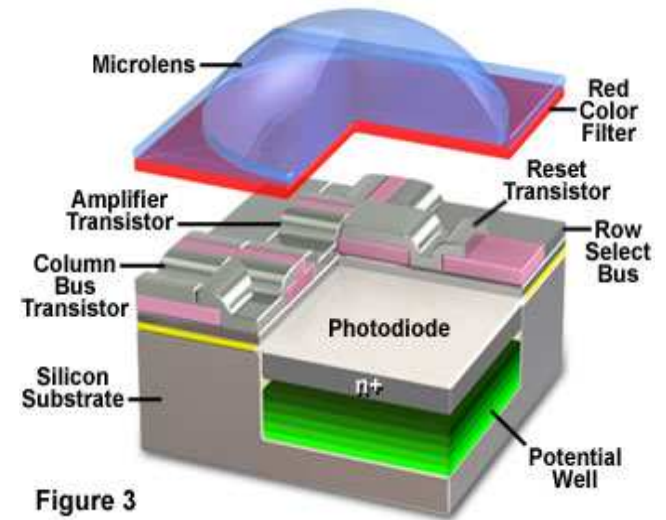
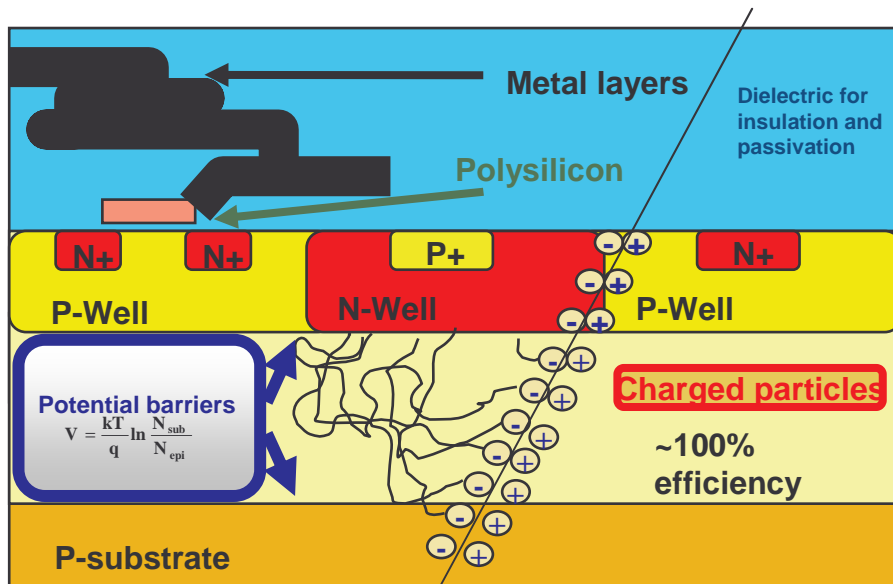


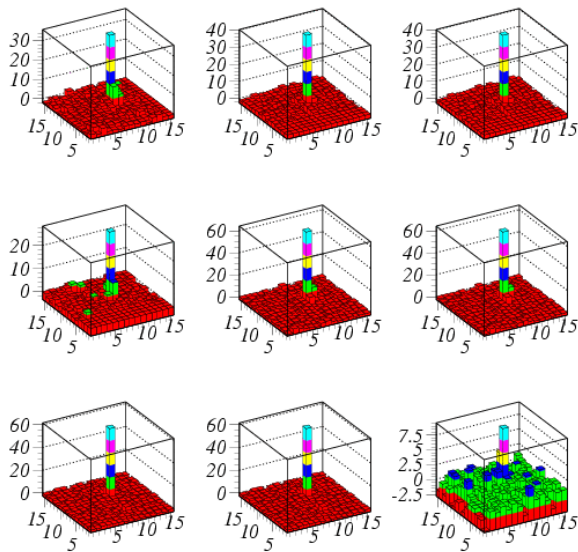
Figure 3



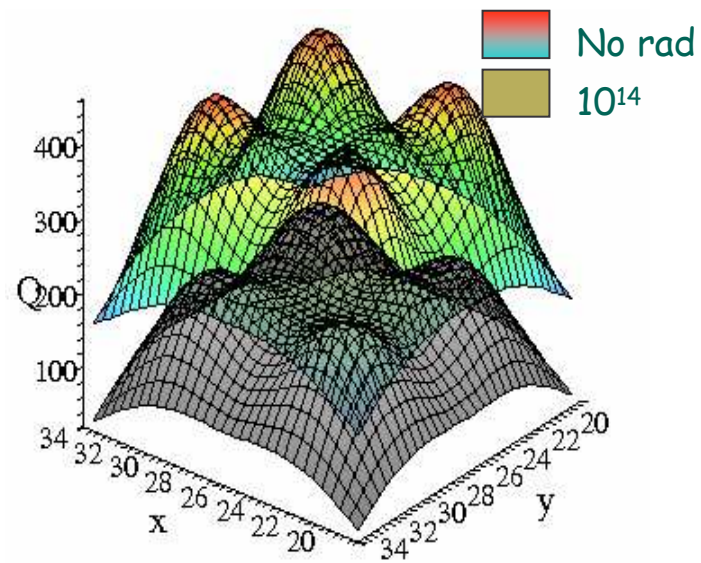
- **HEP** and space applications more recent
 - Detector for higher energy X/gamma-rays or charged particles
 - Basic principle; collection of liberated charge in thin **epitaxial layer** just below surface readout electronics

“MAPS for PP&SS” collaboration

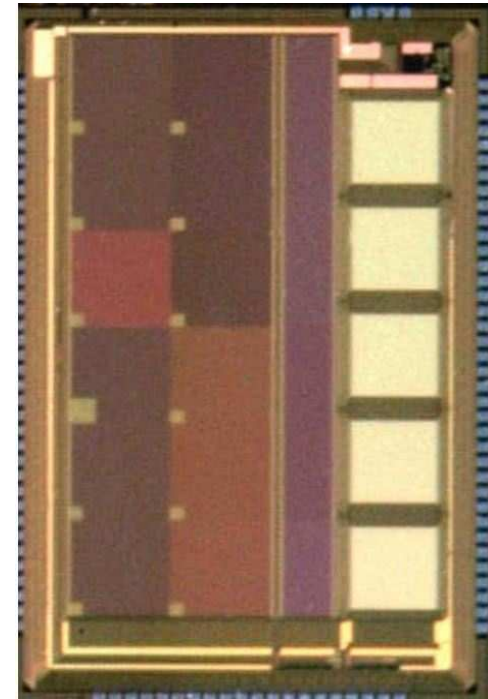
- Birmingham, Glasgow, Leicester (→Brunel), Liverpool, RAL
- Two year programme; June 2003 – May 2005
- **Simulated** and **real** devices studied
- A lot of experience at RAL in areas directly relevant to us



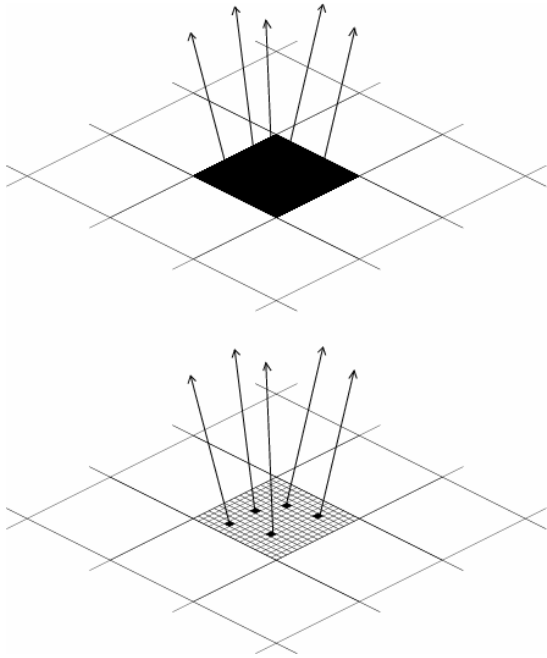
Measurements of S/N with ^{106}Ru



Simulation of charge collection with 4-diode structure before/after irradiation



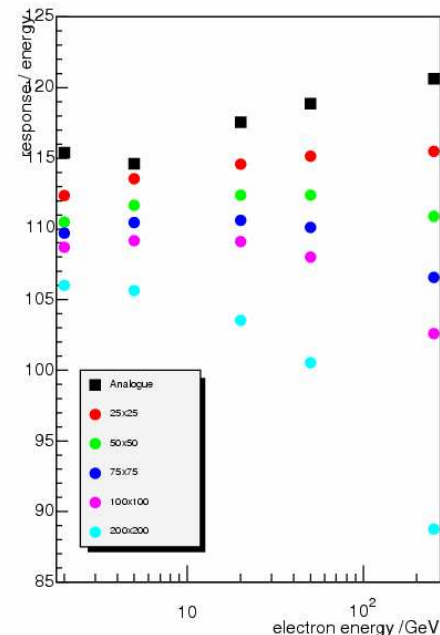
Basic concept for ECAL



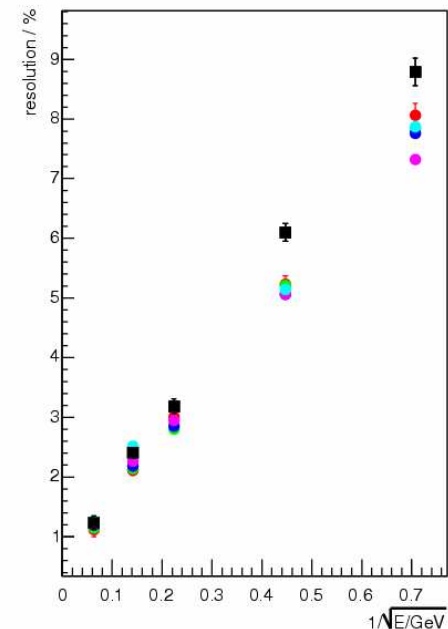
- Replace $1 \times 1 \text{ cm}^2$ diode pads with **much smaller** pixels
- Make pixels small enough that at most one particle goes through each
- Then only need threshold to say if pixel hit or not; “**binary**” readout, i.e. DECAL

- How small is small?
 - EM shower core density at 500 GeV is $\sim 100/\text{mm}^2$
 - Pixels must be $< 100 \times 100 \mu\text{m}^2$; working number is $50 \times 50 \mu\text{m}^2$
 - Gives $\sim 10^{12}$ pixels for ECAL!

Linearity

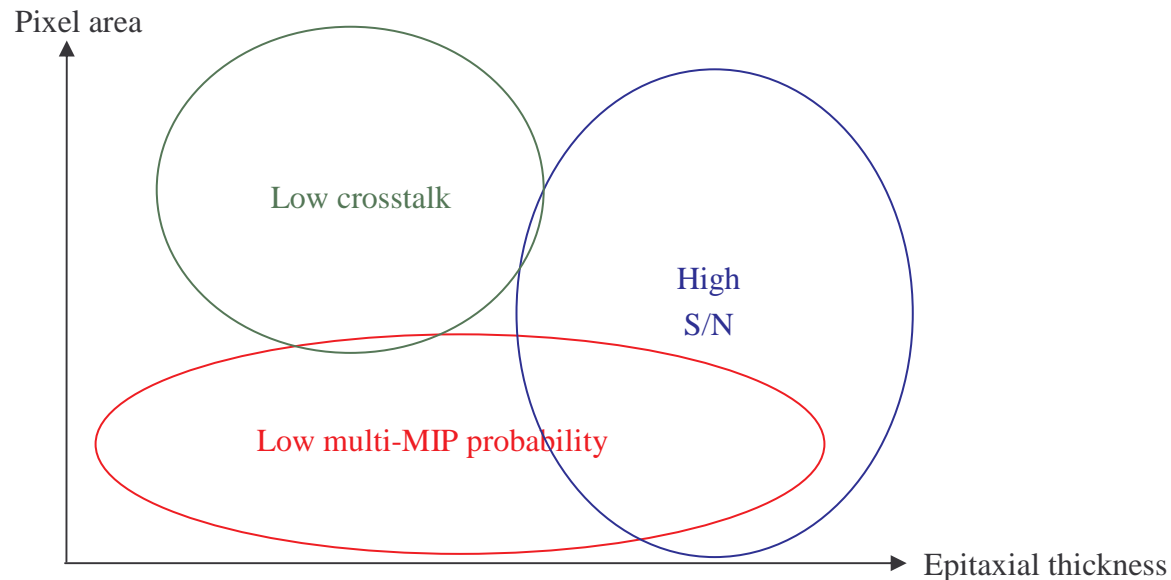


Resolution



Pixel analogue optimisation

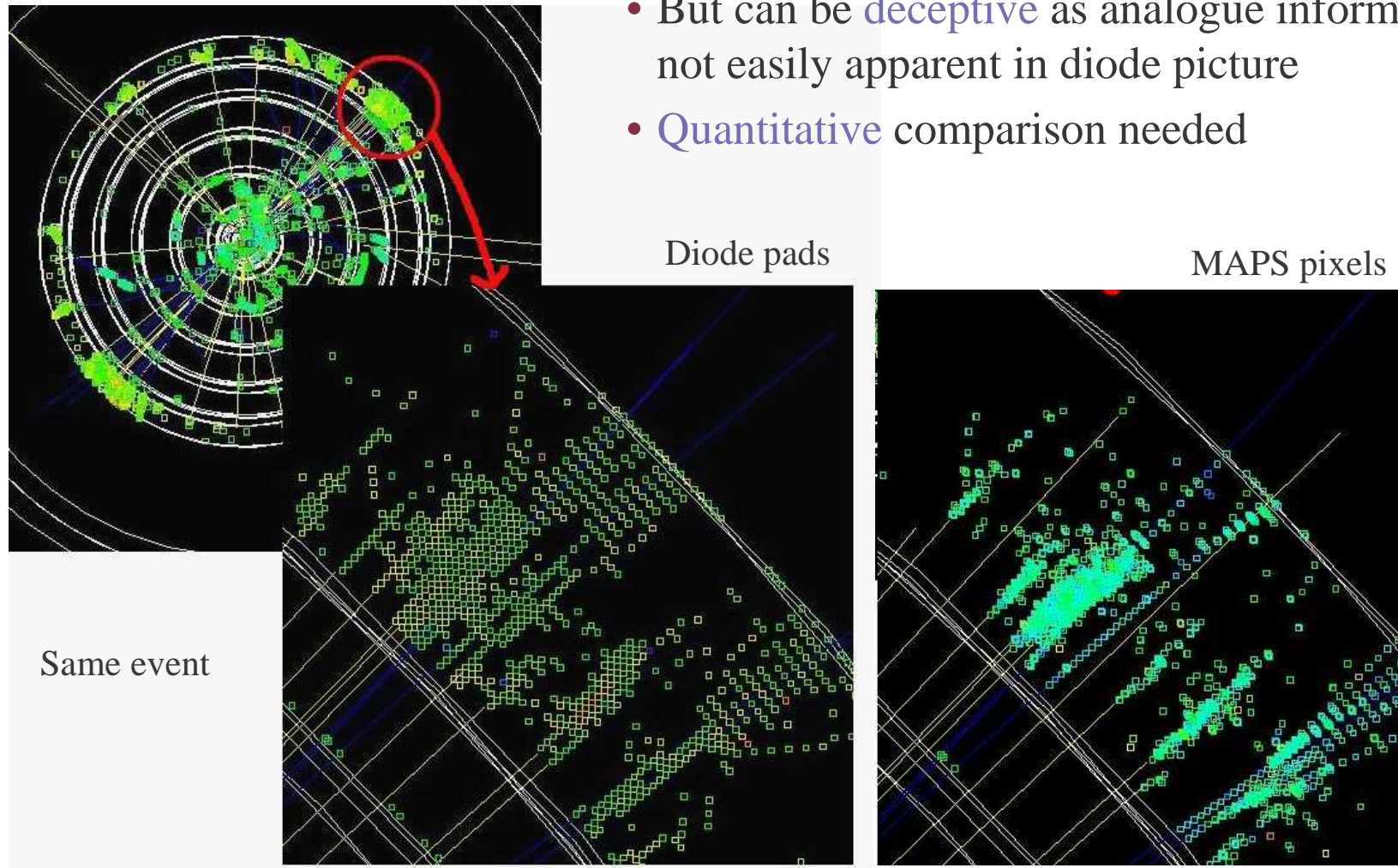
- Studies are needed on
 - Charge sharing (crosstalk), MIP S/N, MIP multiple hits/pixel
 - **Dependent** on pixel area, epitaxial thickness, threshold, diode geometry, etc



- Noise rate target $< 10^{-6}$ ($\sim 5\sigma$); DAQ could handle (at least) $\sim 10^{-5}$
- Large parameter space; need to find best combination
 - **Sensor-level simulation** to interpolate between sensor measurements
 - **Physics-level simulation** needed to guide choices

Physics MC studies in progress

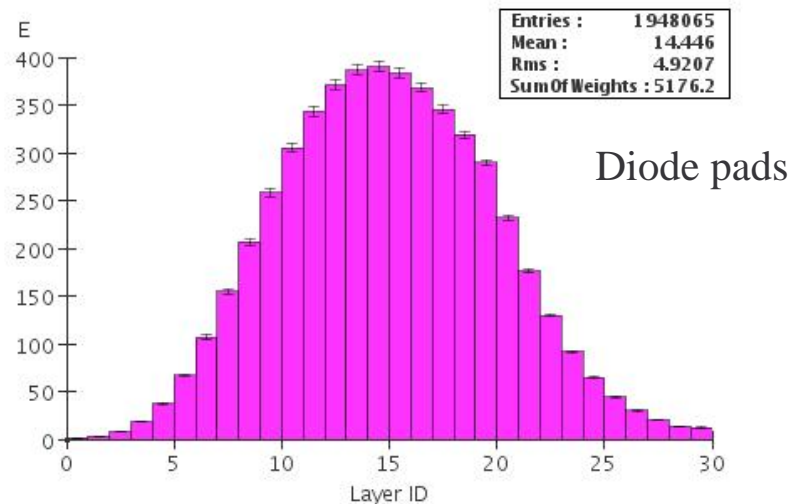
- By eye, pixels look very good compared with diodes
- But can be **deceptive** as analogue information not easily apparent in diode picture
- **Quantitative** comparison needed



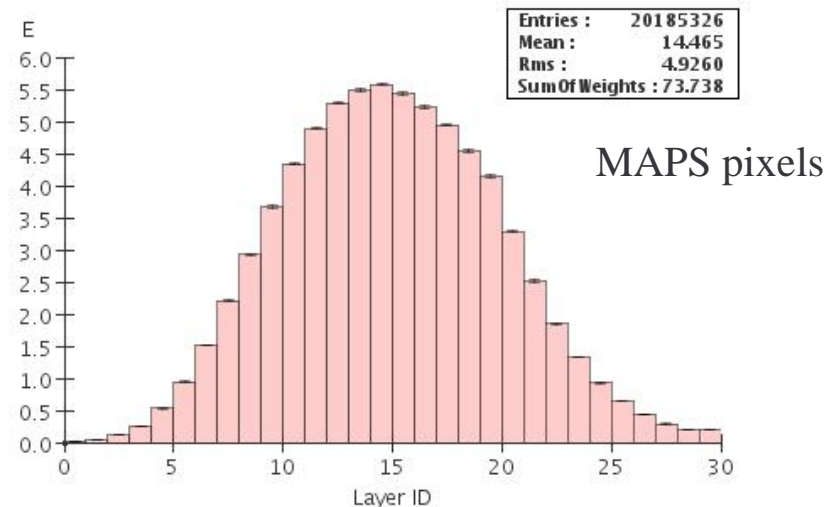
MC studies (cont)

- Compare electron resolution up to **500 GeV**
 - Resolutions **very similar** for diode and MAPS
 - Mainly dominated by fundamental EM shower fluctuations?

SiD ECAL Barrel Energy-Layer distribution for 500 GeV e-



MAPS ECAL Barrel Energy-Layer distribution for 500 GeV



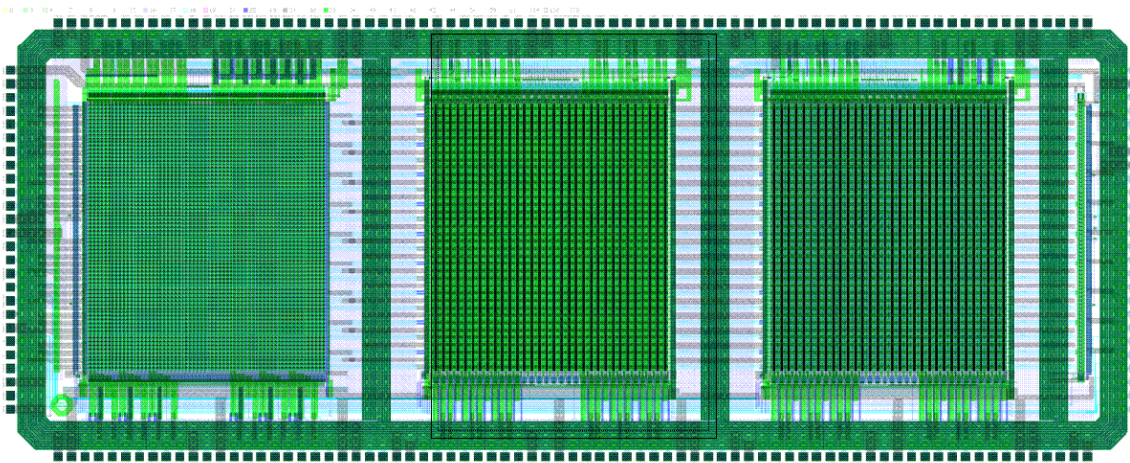
- Need to build up to comparison of ECALs using **hadronic jets** with realistic **PFLOW** algorithm
 - Need very **flexible** PFLOW code to handle both ECALs
 - Much work to be done before this study can be completed

Readout concept

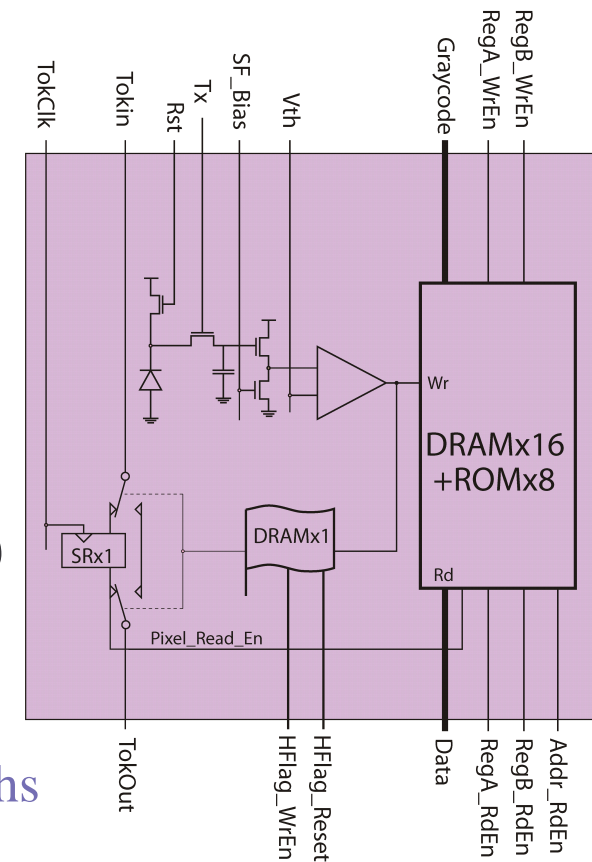
- In reality, will not have single event at a time
 - ILC will have **multiple beam crossings** per train
- **Buffer** results within bunch train, **readout** between trains
 - Must do threshold discrimination for **each beam crossing** in train
 - Store results in **on-pixel memory** until end of train and then flush out
- Could be up to **5000** beam crossings per train
 - Not feasible to build **5kbits** of memory into a $50 \times 50 \mu\text{m}^2$ pixel
 - Assume rate is low and only store beam crossing numbers when hit
 - Memory is then 2 bytes \times maximum number of crossings allowed
- Must know hit rate to determine **maximum memory** needed
 - Presumably dominated by one or more of: beam-induced background, Bhabhas, mini-jets, pixel noise
 - Need good estimates of **rates** of each of these; overlap with WP5

MI³ Collaboration

- Wide ranging (not just PPARC), Basic Technology development
- **RAL ID** a major contributor
 - Design centre for CMOS sensors and leading group in DAQ

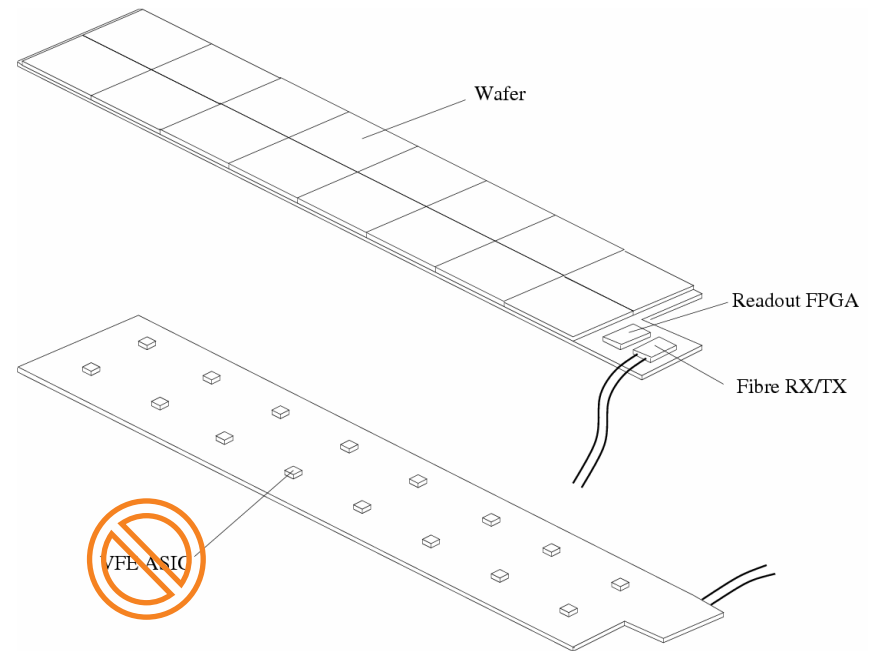


- Current design (by J.Crooks, also on CALICE)
 - Many **similar** features to ILC ECAL requirements...
 - ...but several **differences** also
 - Sensors fabricated and under test over next **few months**
 - **Valuable experience** before starting CALICE design



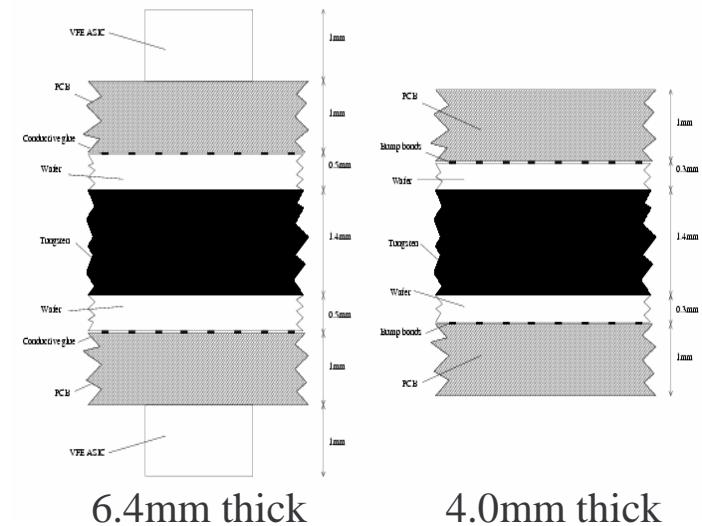
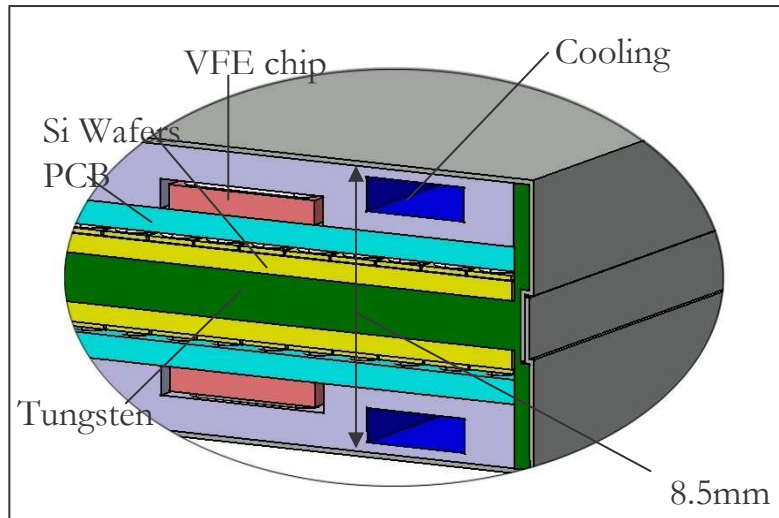
ECAL as a system

- **Replace** diode pad wafers and VFE ASICs with MAPS wafers
 - **Mechanically** very similar; overall design of structure identical
 - **DAQ** very similar; FE talks to MAPS not VFE ASICs
 - Both purely digital I/O, data rates within order of magnitude
- Aim for MAPS to be a “**swap-in**” option without impacting too much on most other ECAL design work
- Requires sensors to be glued/solder-pasted to PCB **directly**
 - No **wirebonds**; connections must be routed on sensor to pads above pixels
 - **New technique** needed which is part of our study



Potential advantages

- Slab **thinner** due to missing VFE ASICs
 - Improved effective **Moliere radius** (shower spread)
 - Reduced size (=cost) of detector magnet and outer subdetectors



- **Thermal coupling** to tungsten easier
 - Most heat generated in **VFE ASIC** or **MAPS comparators**
 - Surface area to slab tungsten sheet $\sim 1\text{cm}^2$ for VFE ASIC, $\sim 100\text{cm}^2$ for final MAPS

- **COST!** Standard CMOS should be cheaper than high resistivity silicon
 - No crystal ball for 2012 but roughly a **factor of two** different now
 - TESLA ECAL wafer cost was **90M euros**; 70% of ECAL total of 133M euros
 - That assumed 3euros/cm² for 3000m² of processed silicon wafers

Other requirements

- Also need to consider power, uniformity and stability
 - **Power** must be similar (or better) than VFE ASICs to be considered
 - Main load from comparator; $\sim 2.5\mu\text{W}/\text{pixel}$ when powered on
 - Investigate switching comparator; may only be needed for $\sim 10\text{ns}$
 - Would give averaged power of $\sim 1\text{nW}/\text{pixel}$, or **0.2W/slab**
 - There will be other components in addition
 - VFE ASIC aiming for $100\mu\text{W}/\text{channel}$, or **0.4W/slab**
 - Unfeasible for threshold to be set per pixel
 - Prefer single DAC to set a comparator level for whole sensor
 - Requires sensor to be **uniform** enough in response of each pixel
 - Possible fallback; divide sensor into e.g. four regions
 - Sensor will also be temperature cycled, like VFE ASICs
 - Efficiency and noise rate must be reasonably **insensitive** to temperature fluctuations
 - More difficult to correct binary readout downstream

Planned programme

- **Two** rounds of sensor fabrication
 - First with **several** pixel designs, try out various ideas
 - Second with **uniform** pixels, iterating on best design from first round
- **Testing** needs to be thorough
 - Device-level simulation to guide the design and understand the results
 - “Sensor” bench tests to study electrical aspects of design
 - Sensor-level simulation to check understanding of performance
 - “System” bench tests to study noise vs. threshold, response to sources and cosmics, temperature stability, uniformity, magnetic field effects, etc.
 - Physics-level simulation to determine effects on ECAL performance
- Verification in a **beam test**
 - Build at least one PCB of MAPS to be inserted into pre-prototype ECAL
 - Replace existing diode pad layer with MAPS layer
 - **Direct comparison** of performance of diode pads and MAPS

First draft of schedule

		FY	5/6			FY	6/7			FY	7/8			FY	8/9	
	1	2	3	4	1	2	3	4	1	2	3	4	1	2	3	4
Feasibility study	=	=	=													
Design 1				=	=	=	=									
Fabrication 1								=	=							
Basic tests 1									=							
Detailed tests 1									=	=	=	=				
Design 2										=	=					
Fabrication 2												=	=			
Basic tests 2													=			
Detailed tests 2													=	=	=	=
Beam test PCB											=	=	=	=		
Beam test															=	=

Schedule implications

- **Design** starting 6 months later than originally planned
 - Limit on RAL ID staff effort in FY05/06
- **First fabrication** and testing starting 6-9 months later
 - Limit on equipment funds in FY06/07
- **Second fabrication** and testing starting 9 months later
 - Knock-on effects from above
- **Beam test** starting 9 months later also
 - Would be ready from Oct 2008
 - Misses scheduled CALICE beam tests at CERN and FNAL
 - Have to arrange for **specific ECAL+MAPS beam test** (at DESY?)

Conclusions

- Basic idea of MAPS seems feasible so far
 - No showstoppers identified (yet!)
- Will continue conceptual study until end of year
 - Had first meeting last week
- Design and fabrication of real sensors will follow
 - RAL/ID effort funded from Jan 2006
- Simulation studies are needed in parallel
 - RAL/PPD will do sensor simulation
 - Good start at Birmingham already on physics studies
 - New RAs at Birmingham and Imperial should contribute soon